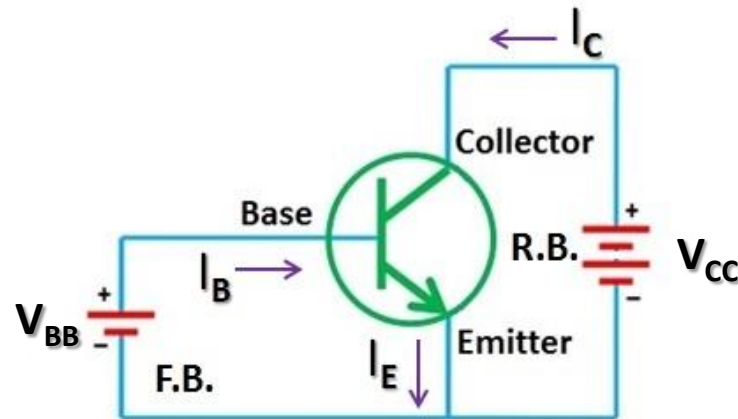


UNIT 3

Bipolar Junction Transistor

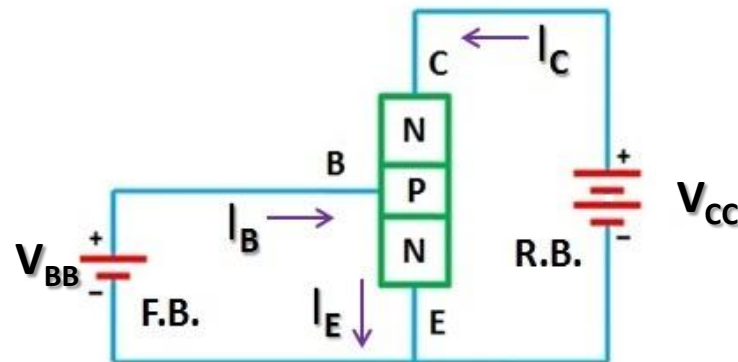
Common-Emitter Configuration

NPN- Common Emitter (CE) Configuration



$$I_E = I_C + I_B$$

Since I_B is very small
 $I_C \approx I_E$ (approx.)



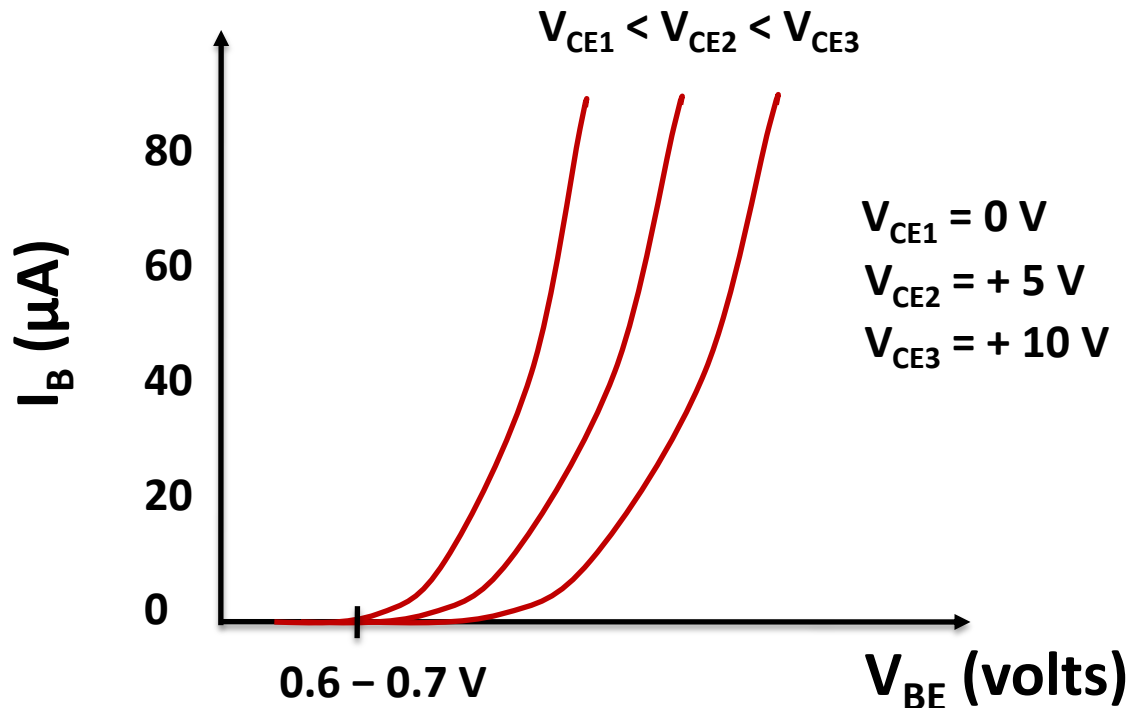
- CE Configurations have different voltage arrangements for NPN and PNP, such that
 - For Active Region operation of CE Configuration-----
 - Input Section is always Forward Biased (F.B.) &
 - Output Section is always Reverse Biased (R.B.)

Current-Voltage (I-V) Characteristics of NPN – CE configuration

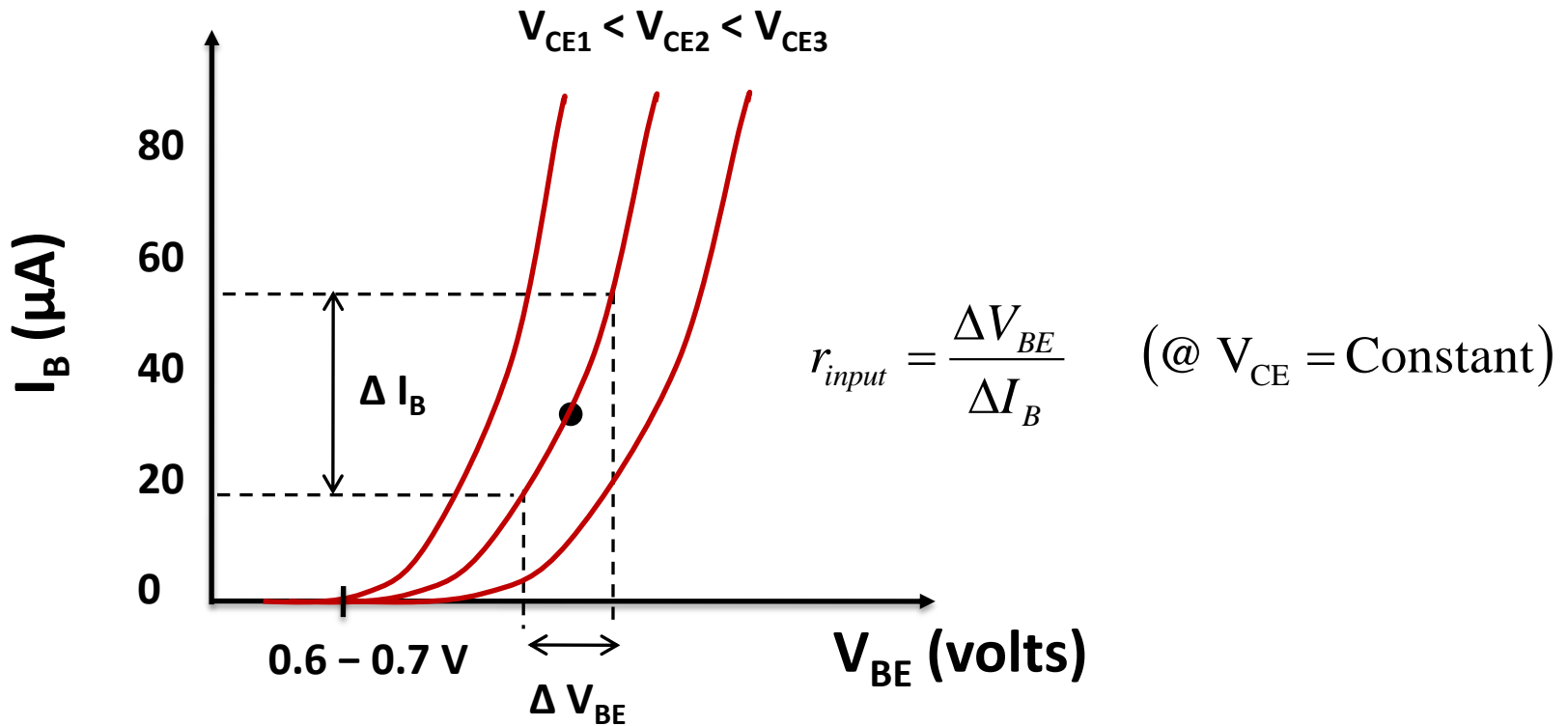
- **Input (or Base) Static Characteristics:**

- Input Current (I_B) vs Input Voltage (V_{BE})

- @ Constant value of Collector-Emitter Voltage (V_{CE}) for each curve



Input (or Base) Static Characteristics



- Dynamic Input Resistance (r_{input}) can be calculated from I/P characteristics
- It varies with the point of measurement
- Typical values of r_{input} are $\approx 1 \text{ K}\Omega$
- So, Input Resistance of CE config. is although Low but higher than that of CB Config.

Input (or Base) Static Characteristics

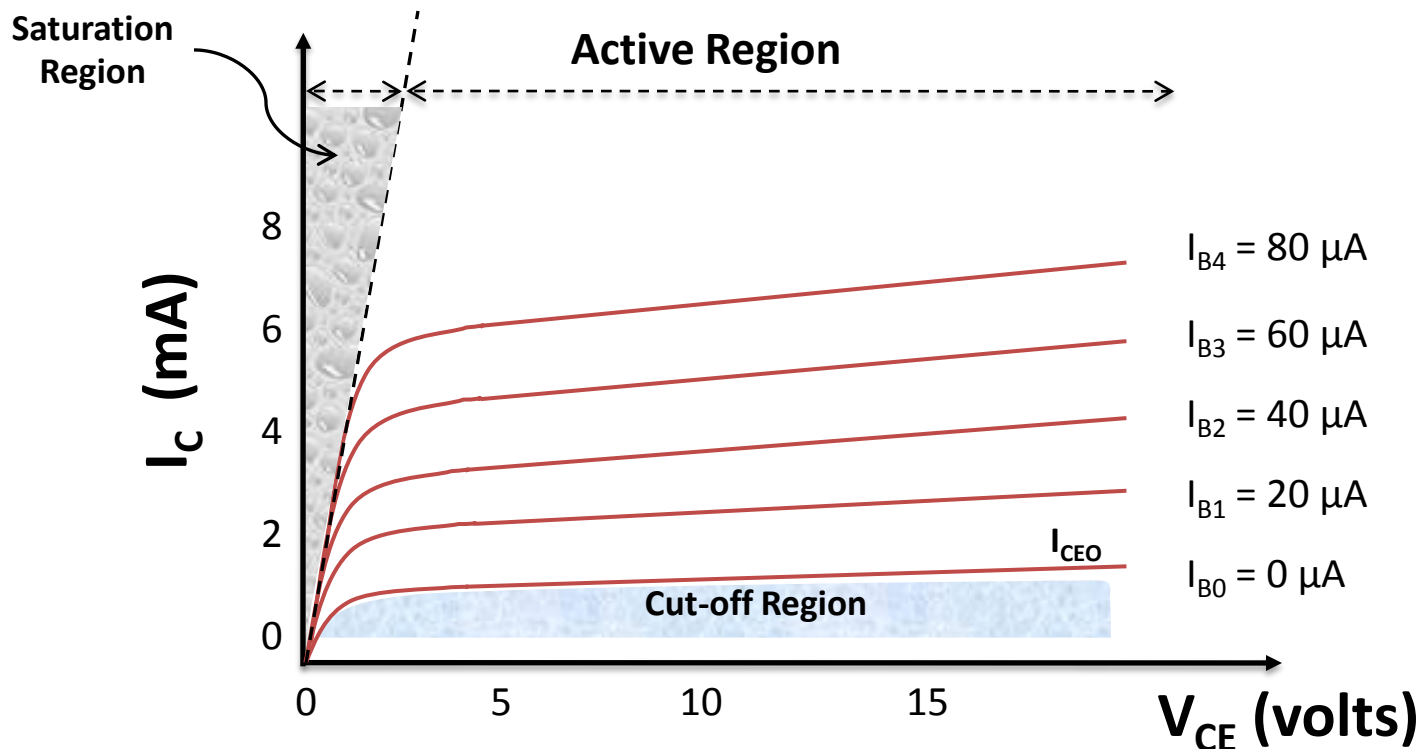
- **Represents simply the Forward Characteristics of Base-Emitter Diode (@ various Collector-Emitter Voltages)**
- Threshold Voltage below which I_B is Very Small
---- 0.6 – 0.7 V (Si) and 0.1 – 0.2 V (Ge) materials
- If $V_{CE} = 0$ (Collector shorted to Emitter) & Base-Emitter Jn. Forward Biased, Input characteristics are simply of a Forward-Biased PN-Diode
- $I_B = 0$ if both V_{BE} & V_{CE} are Zero (i.e. Both Jn. are shorted)
- I_B decreases with increase in V_{CE} (@ constant V_{BE}), due to modulation of Base width (“Early Effect”)
- So, Input Curves will shift towards right as V_{CE} Increases.

Current-Voltage (I-V) Characteristics of NPN – CE configuration

- **Output (or Collector) Static Characteristics:**

- Output Current (I_C) vs Output Voltage (V_{CE})

- @ Constant value of Base Current (I_B) for each curve



Output (or Collector) Static Characteristics

- Divided into 3 Regions: - Active Region, - Saturation Region, - Cutoff Region

	Active Region	Saturation Region	Cutoff Region
Base-Emitter	Forward Biased	Forward Biased	Reverse Biased
Collector-Emitter	Reverse Biased	Forward Biased	Reverse Biased

Active Region:

- Area between the “Saturation & Cutoff Regions”
- Input Current is now I_B , and Output current is now I_C
- I_B is very small (in tens of μA), however I_C is Large (in mA)
- This results in Amplification of current-**Transistor Amplifying Action**
- **Current Equations are:**

$$I_E = I_C + I_B \quad \& \quad I_C = \alpha_{dc} I_E + I_{CO} \quad (1)$$

$$\text{So,} \quad I_C = \alpha_{dc} (I_C + I_B) + I_{CO} \quad (2)$$

$$\text{Or,} \quad (1 - \alpha_{dc}) I_C = \alpha_{dc} I_B + I_{CO} \quad (3)$$

Relation Between α_{dc} and β_{dc}

$$I_C = \frac{\alpha_{dc}}{1 - \alpha_{dc}} I_B + \frac{1}{1 - \alpha_{dc}} I_{CO}$$

(4)

- Let us define β_{dc} as “Common-Emitter dc Current Gain” or simply “dc beta”

$$\beta_{dc} = \frac{I_C - I_{CEO}}{I_B} \approx \frac{I_C}{I_B} \quad (\text{as } I_{CEO} \ll I_C) \quad \beta_{dc} = \frac{\alpha_{dc}}{1 - \alpha_{dc}}$$

(5)

- and “Reverse Leakage Current between Collector & Emitter as I_{CEO} ”

$$I_{CEO} = \frac{1}{1 - \alpha_{dc}} I_{CO}$$

(6)

- where, $I_{CO} = I_{CBO}$ (since $\alpha_{dc} \approx 0.95$, $I_{CEO} \gg I_{CBO}$) is Reverse Leakage Current between Collector & Base

$$I_C = \beta_{dc} I_B + I_{CEO} = \beta_{dc} I_B + (1 + \beta_{dc}) I_{CO} \approx \beta_{dc} I_B \quad \text{as } I_B \gg I_{CO}$$

(7)

Relation Between α and β

$$I_C = \frac{\alpha}{1-\alpha} I_B + \frac{1}{1-\alpha} I_{CO}$$

(4.1)

- Let us define β as “Small Signal Common-Emitter ac Current Gain” or simply “ac or dynamic beta”

$$\beta = \frac{\Delta I_C}{\Delta I_B}$$

(@ Constant V_{CE})

$$\beta = \frac{\alpha}{1-\alpha}$$

(5.1)

- and “Reverse Leakage Current between Collector & Emitter as I_{CEO} ”

$$I_{CEO} = \frac{1}{1-\alpha} I_{CO}$$

(6.1)

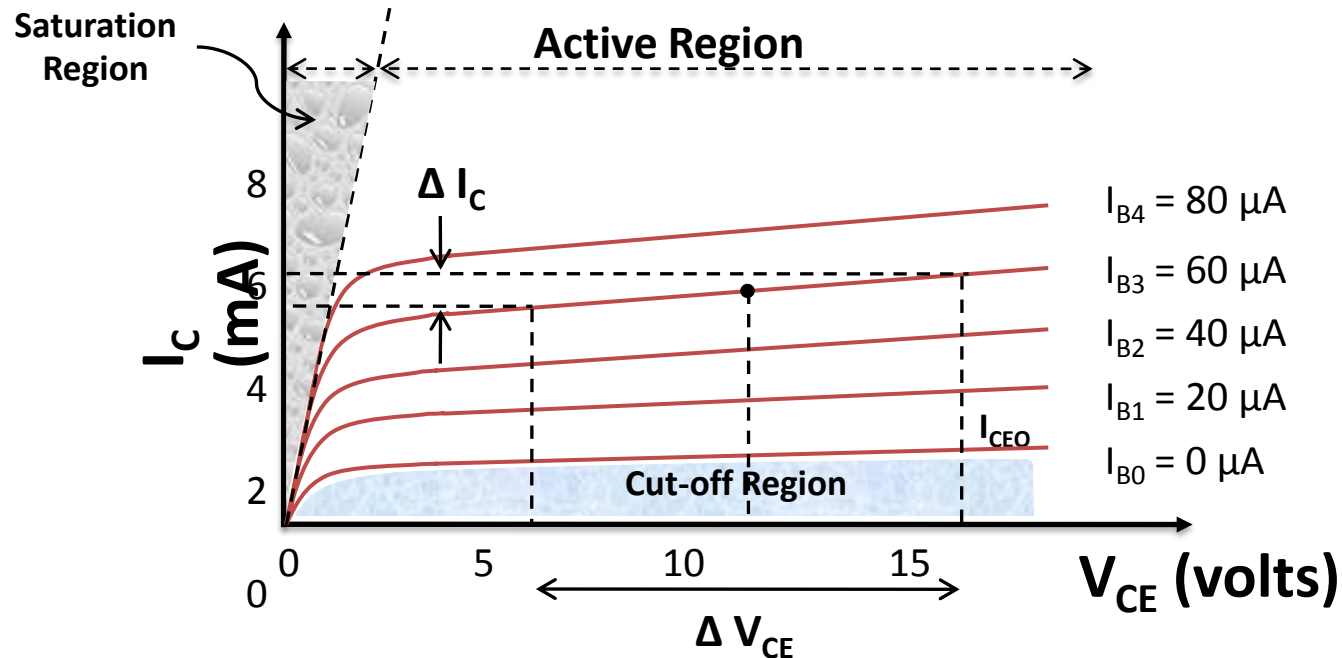
- where, $I_{CO} = I_{CBO}$ (since $\alpha_{dc} \approx 0.95$, $I_{CEO} \gg I_{CBO}$) is Reverse Leakage Current between Collector & Base, Therefore,

$$I_C = \beta I_B + I_{CEO} = \beta I_B + (1 + \beta) I_{CO} \approx \beta I_B \quad \text{as } I_B \gg I_{CO}$$

(7.1)

Output (or Collector) Static Characteristics

$$r_{output} = \frac{\Delta V_{CE}}{\Delta I_C} \quad (@ I_B = \text{Constant})$$



- Dynamic Output Resistance (r_{output}) can be calculated from O/P characteristics $\approx 20 \text{ K}\Omega$
- So, Output Resistance of CE config. is Quite Large, but not that large of CB Config. Since α is not perfectly constant ≈ 0.98 (usually range between 0.90 – 0.995), hence even small variation in it can cause large Variations in the values of β (as per relation (5)/(5.1))

Output (or Collector) Static Characteristics

Saturation Region:

- **Both B-E and C-E Junctions are Forward –Biased**
- As V_{CB} becomes few tens of a Volt (such that $V_{CE} < V_{BE}$),
 - I_C decreases rapidly as V_{CE} decreases
- I_C is almost independent of I_B

Cutoff Region:

- **Both B-E and C-E Junctions are Reverse –Biased**
- Only Reverse Leakage/Saturation Current $I_{CEO} = (1+\beta) I_{CBO}$ flows in the output circuit

Parameters from Output Characteristics

$$r_{output} = \frac{\Delta V_{CE}}{\Delta I_C} \quad (@ I_B = \text{Constant})$$

$$\beta_{dc} = \frac{I_C}{I_B} \quad (@ V_{CE} = \text{Constant})$$

$$\beta = \frac{\Delta I_C}{\Delta I_B} \quad (@ V_{CE} = \text{Constant})$$